



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: David M. Curran, et al. Docket No: TI-29038
Serial No: 10/029,788 Conf. No: 5683
Examiner: Timothy V. Eley Art Unit: 3724
Filed: 10/26/2001
For: METHOD FOR REDUCING THE THICKNESS OF SPIN-ON GLASS ON SEMICONDUCTOR WAFERS

NOTICE OF APPEAL FROM THE PRIMARY EXAMINER
TO THE BOARD OF APPEALS

Mail Stop AF
Commissioner For Patents
P.O. Box 1450
Alexandria, VA 22313-1450

MAILING CERTIFICATE UNDER 37 C.F.R. § 1.8(a)
I hereby certify that the above correspondence is being deposited with the U.S. Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on 3-29-04.

Ann Trent
Ann Trent

Dear Sir:

Applicants hereby appeal to the Board of Appeals from the decision of the Primary Examiner mailed December 31, 2003, finally rejecting Claims 1-8 and 15-20.

The item(s) checked below are appropriate:

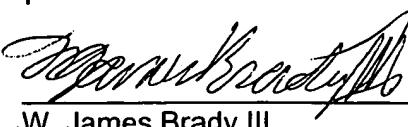
1. An extension of time to respond to the final rejection
 was granted on _____
 is requested for ____ month.
2. A timely response to the final rejection has been ~~TECHNOLOGY CENTER H3700~~
3. Fee \$330.00:
 Not required (Fee paid in prior appeal)
 The Commissioner of Patents is hereby authorized to charge any fees which may be required or credit any overpayment to the deposit account of Texas Instruments Incorporated, Account No. 20-0668.
This form is submitted in triplicate.

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